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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/762,826	CHAN ET AL.	
Examiner	Art Unit	
George P. Koch III	1734	

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Class	Subclass	Date	Examiner	
156	351, 358, 360, 378, 379	1/13/2004	GRK	
73	1.15	1/16/2004	GRK	
73	862.381	1/16/2004	GRK	
702	41,42,44	1/16/2004	GRK	
702	97	1/16/2004	GRK	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SEA	RCH STRATEGY	()
	DATE	EXMR
East Text Search	1/16/2004	GRK
Inventor Name Search	1/17/2004	GRK
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